

PHASE DIFFERENCE MICROSCOPE

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Abstract

PROBLEM TO BE SOLVED: To provide a microscope capable of accurately extracting phase distribution even when both of amplitude distribution and phase distribution coexist in an object to be observed.

SOLUTION: By changing the phase difference quantity of a phase plate 4, at least three phase difference images having different phase difference quantities are successively picked up by an image pickup element 6 and stored in a storage means 7. Based on at least three pieces of image information stored, intensity change at respective points on an image surface caused by the change of the phase difference quantity of the phase plate 4 is obtained by a processing means 8, and the intensity change is processed by a stripe scanning technique so as to extract the phase distribution information of the object to be observed 5.

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